

<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10749240	AWN, KIL-JAE
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
180	277	10/27/2006	HK
180	279	10/27/2006	HK
180	326	10/27/2006	HK

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Part of Paper No.: 20061031

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Notes	Date	Examiner
74/\$ (no search) (consulted David Fenstermacher)	10/27/2006	HK
180/271,277,279,282 (consulted Faye Fleming)	06/13/2006	HK
180/326+ (consulted Brian Sircus)	10/27/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/27/2006	HK

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